

Search Notes

Application/Control No.

10/802,735

Examiner

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Applicant(s)/Patent under
Reexamination

TAKAFUJI ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
257	59, 64, 66, 69, 70, 72, 347	8/1/2006	TT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR